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Lu, W.; Wu, W.; Sakauchi, M.;

Document Analysis and Recognition, 1995., Proceedings of the Third International Conference on Volume 1, 14-16 Aug. 1995 Page(s):512 - 515 vol.1

Digital Object Identifier 10.1109/ICDAR.1995.599046

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Verykios, V.S.; Houstis, E.N.; Tsoukala, L.H.; Pantazopoulos, K.N.;

Systems, Man and Cybernetics, Part A, IEEE Transactions on Volume 31, Issue 6, Nov. 2001 Page(s):573 - 586

Digital Object Identifier 10.1109/3468.983414

[AbstractPlus](#) | [References](#) | Full Text: [PDE\(347 KB\)](#) IEEE JNL**3. Rule generation for hierarchical fuzzy systems**

Holve, R.;

Fuzzy Information Processing Society, 1997. NAFIPS '97. 1997 Annual Meeting of the North American Fuzzy Information Processing Society, 21-24 Sept. 1997 Page(s):444 - 449

Digital Object Identifier 10.1109/NAFIPS.1997.624082

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